

4/23/2015



**RELIABILITY MONITOR REPORT
FOR**

MFN 2.2um Silicon Gate (C3)

MAXIM INTEGRATED

**160 RIO ROBLES
SAN JOSE, CA 95134**

**This Report was prepared by
MAXIM INTEGRATED Reliability Engineering**

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

MAX3222EUP+	MAX3243ECAI+
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The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 18479 QUANTITY: 240 FAILS: 0 FITS: 6.2

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 4/1/2014 and 3/31/2015 .

Process Information:

Process Description: MFN 2.2um Silicon Gate (C3)

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1342	MAX3243ECAI+G2X	135°C	192 HRS	80	0	JALT4Q001GQ
HIGH TEMP OP LIFE	1438	MAX3222EUP+	135°C	500 HRS	80	0	JABA22144I
HIGH TEMP OP LIFE	1438	MAX3222EUP+	135°C	500 HRS	80	0	JABA22144H
Total:						0	
FAILURE RATE:	MTTF (YRS): 18479		QUANTITY: 240	FAILS: 0	FITS: 6.2		